

Abstracts

Picosecond Dual-Source Interferometer Extending Fourier-Transform Spectrometer to Microwave Regime

D.W. Van Der Weide and F. Keilmann. "Picosecond Dual-Source Interferometer Extending Fourier-Transform Spectrometer to Microwave Regime." 1996 MTT-S International Microwave Symposium Digest 96.3 (1996 Vol. III [MWSYM]): 1731-1734.

We report a dual-source interferometer based on nonlinear transmission lines and integrated antennas which interfaces directly with a Fourier-transform infrared (FTIR) spectrometer to enable longer-wavelength measurements than normally possible with a black-body source. As a demonstration, we show preliminary transmission measurements through a plate of high-resistivity silicon.

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